## TABLE I. DEVICE PARAMETERS 1/

JPL PART #	MFG	MFG PART #	PACKAGE	DETAIL	ELECTRICAL	RADIATION
ST11731-			STYLE	SCREENING	CHARACTERISTICS &	(TID) LEVEL
			2/	TESTS	GROUP A TESTS	RAD(Si)
DN5283AR	CDI/KNX	1N5283	DO-7	MIL-S-	MIL-S-195ØØ/463	1ØØk <u>3</u> /
DN5283AR through	CDI/KNX	1N5283 through	DO-7	MIL-S- 195ØØ/463	MIL-S-195ØØ/463 (TABLE I)	1ØØk <u>3</u> /

## NOTES:

- 1/ This drawing in conjunction with CS515581, imposes all requirements for procurement of these devices.
- 2/ Device physical dimensions shall conform to MIL-S-195ØØ/463, Figure 1.
- 3/ Sufficient radiation tolerance to this TID level is guaranteed by design for this device. (See CS515581, Paragraph 4.7.7).
- 4. Final finish of leads shall be hot solder dip in accordance with MIL-S-195ØØ.
- 5. This standard takes precedence over documents referenced herein.

RELEASED THRU SE	CTION 356 DATA MANAGEMENT:	DATE:	DATE:		
REVISION: D	APPROVED BY:	DATE:			
	APPROVED SOURCE(S)		THE ITEM LISTED IN THE APPROVED SOURCE BLOCK AND IDENTIFIED BY VENDOR NAME, ADDRESS, AND PART NUMBER WILL BE EVALUATED AND TESTED BY THE JPL ELECTRONIC PARTS RELIABILITY SECTION OR ITS DELEGATED ALTERNATE BEFORE BEING APPROVED FOR USE. NON-JPL USERS SHALL CHECK WITH THE ELECTRONIC PARTS RELIABILITY SECTION ON THE STATUS OF THE PART'S APPROVAL BEFORE USING.		
VENDOR PART NO	VENDOR	JPL PART NO			
JET PROP	ULSION LABORATORY CALIFORI	NIA INSTITUTE OF TECHNOL	OGY CAGE NO 23835		
Procurement specification: CS515581 Screening specification: ZPP-2Ø73-GEN	TITLE:  DIODE, FIELD  CURRENT REGULA	-	DETAIL SPECIFICATION		
			ST 11731		
Custodian: Electronic Parts Reliability Section 514	1		SHEET 1 OF 1		